
**Surface chemical analysis — X-ray
photoelectron spectrometers —
Calibration of energy scales**

*Analyse chimique des surfaces — Spectromètres de photoélectrons X —
Étalonnage en énergie*



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ISO copyright office
Case postale 56 • CH-1211 Geneva 20
Tel. + 41 22 749 0111
Fax + 41 22 749 0947
E-mail copyright@iso.org
Web www.iso.org

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